

AFM "PeakForce" characterization of polyaniline-based ammonia sensors

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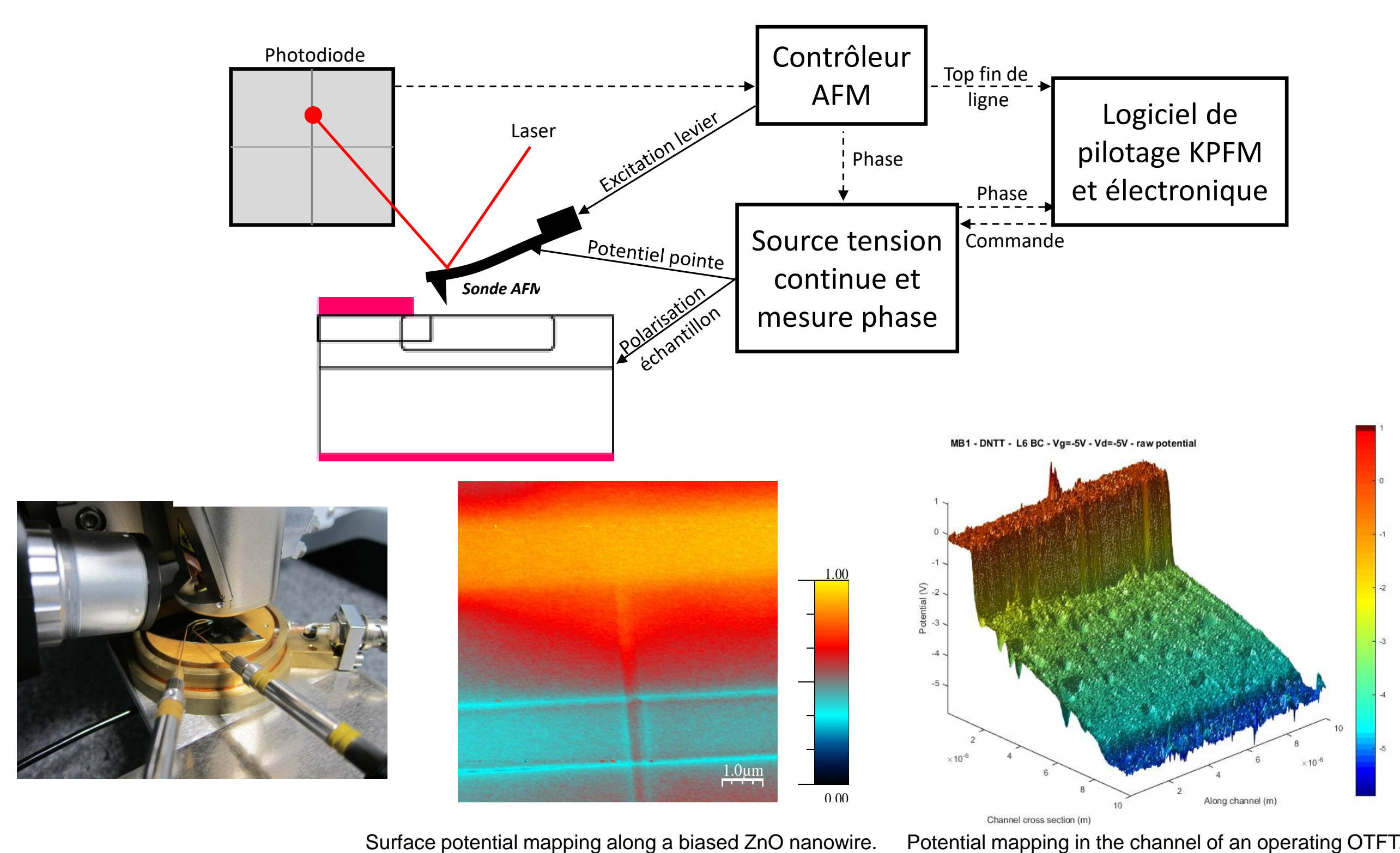
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- AFM-PeakForce technique is used for the characterization of PANi-based ammonia sensor active layers
- Simultaneous and nm-scale resolution topography, electric potential, and mechanical surface properties are measured to study PANi:CSA-PU composite thin films

KPFM

Quantitative measurement of surface potential:

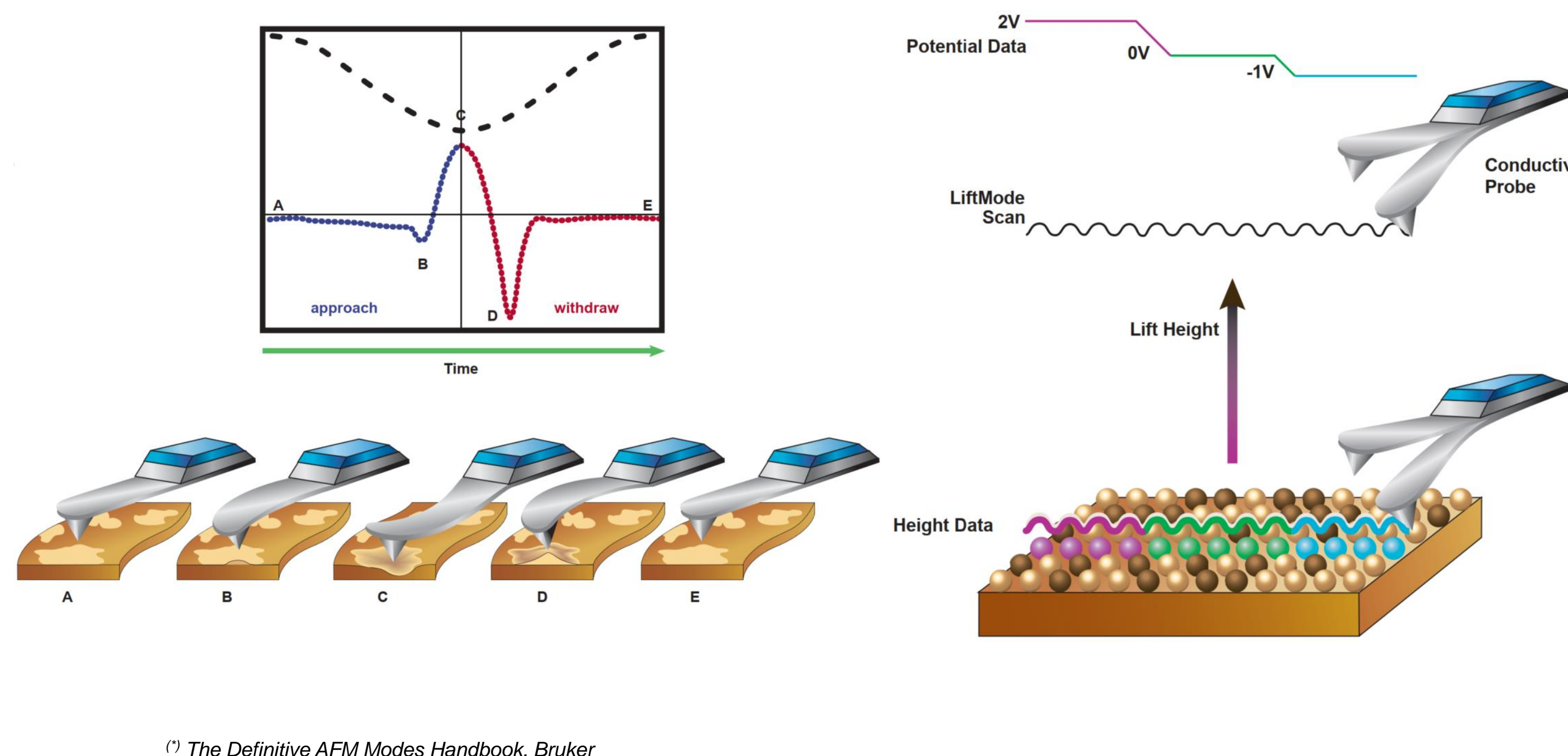
- Device can be operating (biased) during measurement
- ~50 nm lateral resolution



PeakForce

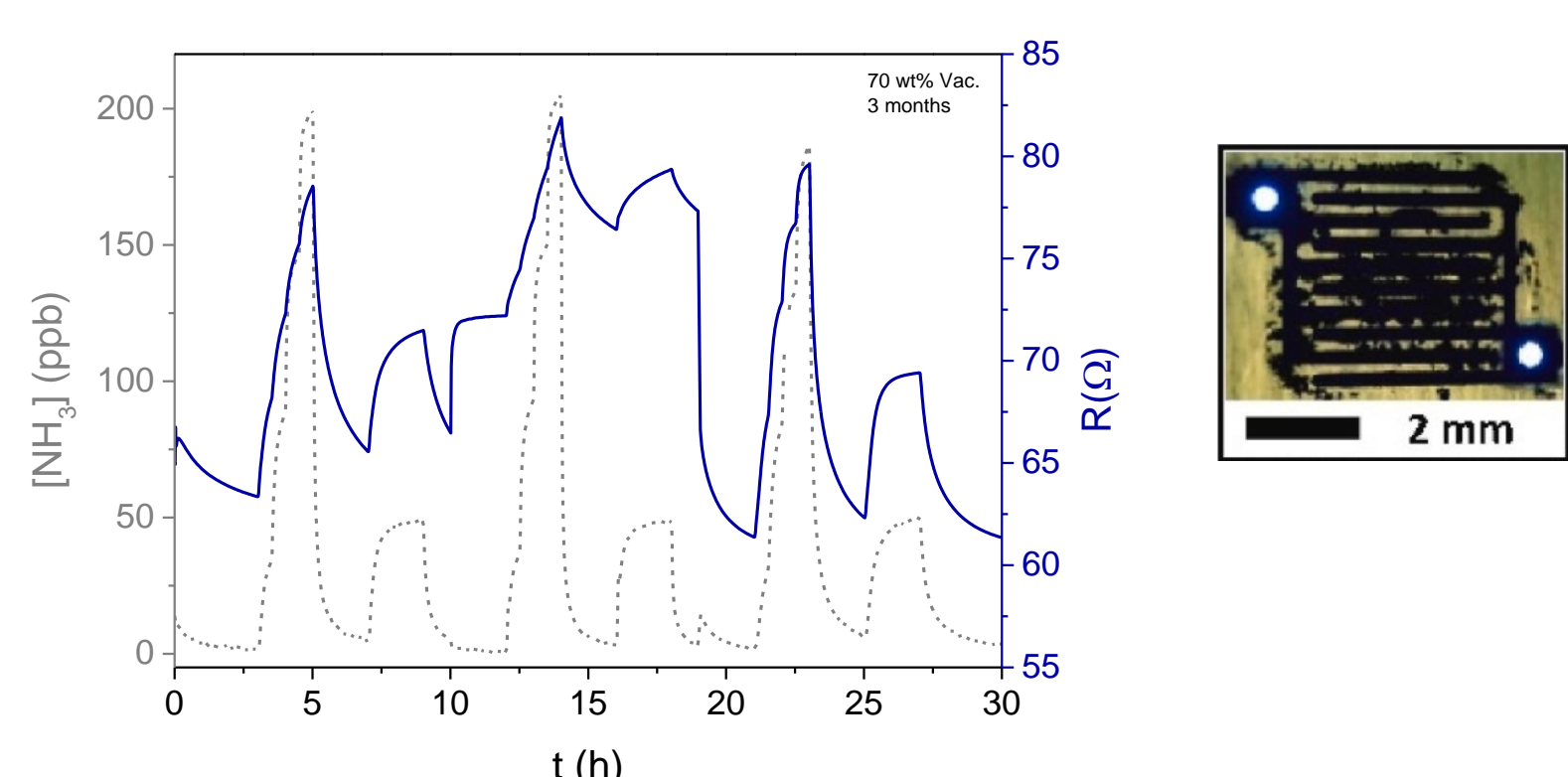
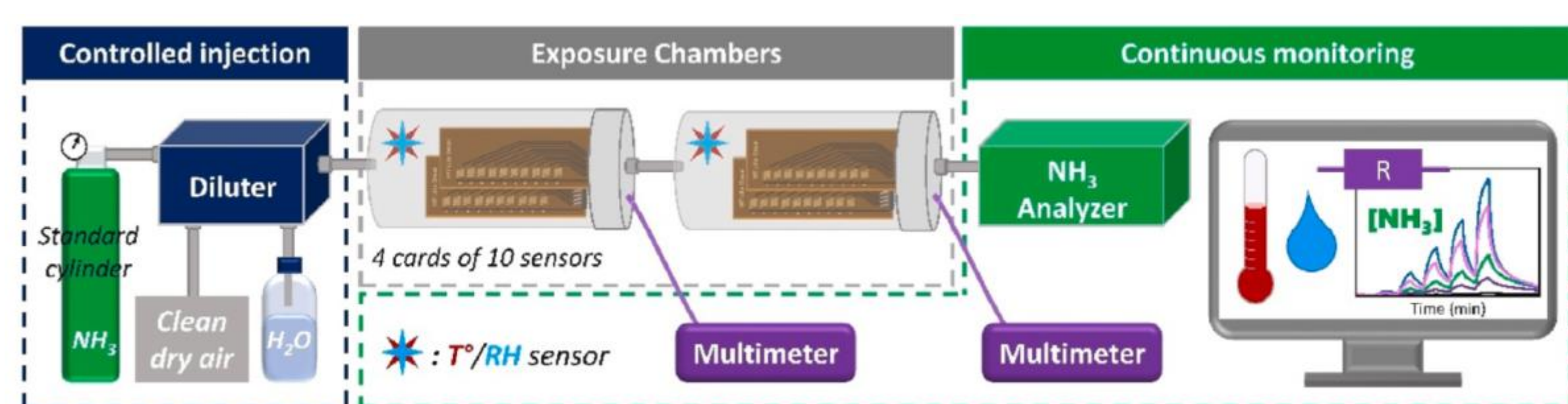
Allows measurement of topography, electrical and mechanical surface properties at the nanoscale*

- Simultaneous mappings
- nm-scale resolution

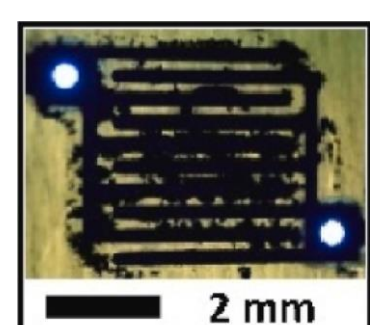


PANi:CSA-PU based ammonia sensors

- Experimental set-up used to assess the detection performances of the sensors.

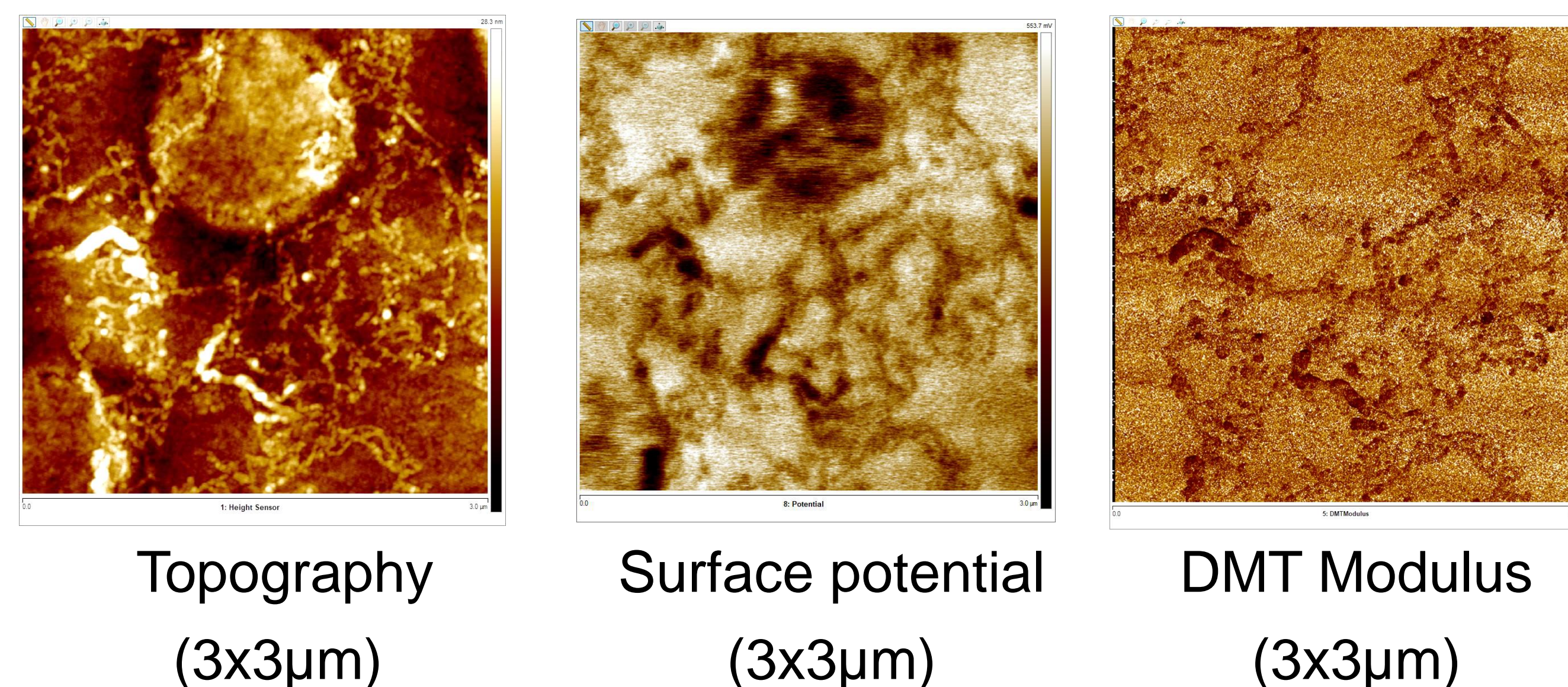
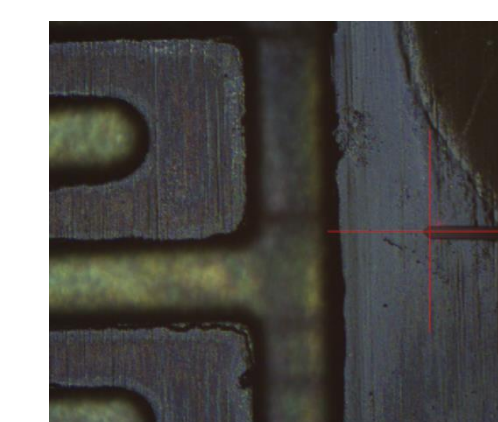


- CSA-based sensors demonstrate high reversibility and repeatability.



Peak force AFM measurements

- Topography, electric potential and mechanical properties of the composite PANi:CSA-PU layers
- Understanding of the layer structure as a function of the PU concentration.



- The PeakForce technique allows high spatial resolution characterization of composite materials such as PANi:CSA-PU. The correlation between topography, surface potential, and mechanical properties offers a unique and powerful tool to analyse the thin film local composition and properties